

Notice of References Cited	Application/Control No. 10/730,343	Applicant(s)/Patent Under Reexamination FURTH ET AL.	
	Examiner Jason M Han	Art Unit 2875	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,167,447	12-1992	Gonzales, Luis J. M.	362/202
	B	US-6,388,390	05-2002	Rachwal, Erwin J.	315/200R
	C	US-5,489,485	02-1996	Peot et al.	429/99
	D	US-4,563,727	01-1986	Curiel, Raymond F.	362/183
	E	US-5,606,238	02-1997	Spellman et al.	320/110
	F	US-5,686,811	11-1997	Bushong et al.	320/110
	G	US-2003/0189826	10-2003	Yoon, Sang-Yeon	362/205
	H	US-2004/0090777	05-2004	Lee, Wen-Sung	362/202
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000-208117	07-2000	Japan	Yamazaki Yoichi	H01M 2/10
	O	2000-040402	02-2000	Japan	Gomi Tatsuhiko	F21L 4/00
	P	10-144273	05-1998	Japan	Saikawa Isao	H01M 2/10
	Q	09-320552	12-1997	Japan	Imao Tadatomo	H01M 2/10
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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